

<b>Notice of References Cited</b>	Application/Control No. 10/729,558		Applicant(s)/Patent Under Reexamination YOON ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,451,453	11-2008	Evans et al.	719/318
*	B	US-7,392,481	06-2008	Gewickey et al.	715/716
*	C	US-7,188,193	03-2007	Getsin et al.	709/248
*	D	US-7,448,021	11-2008	Lamkin et al.	717/115
*	E	US-7,197,234	03-2007	Chatterton, Geoff	386/95
*	F	US-2004/0096199	05-2004	Chou et al.	386/125
*	G	US-2002/0122658	09-2002	Fukuda et al.	386/95
*	H	US-6,138,175	10-2000	deCarmo, Linden A.	710/5
*	I	US-7,197,234	03-2007	Chatterton, Geoff	386/95
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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